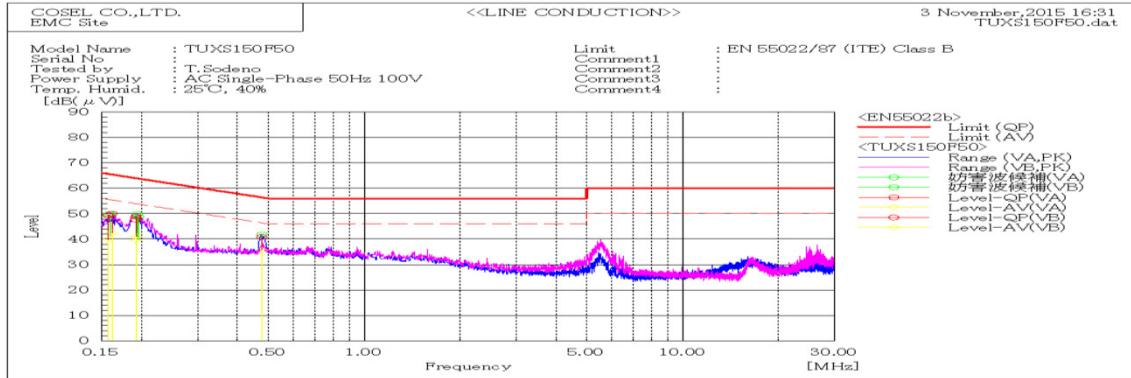
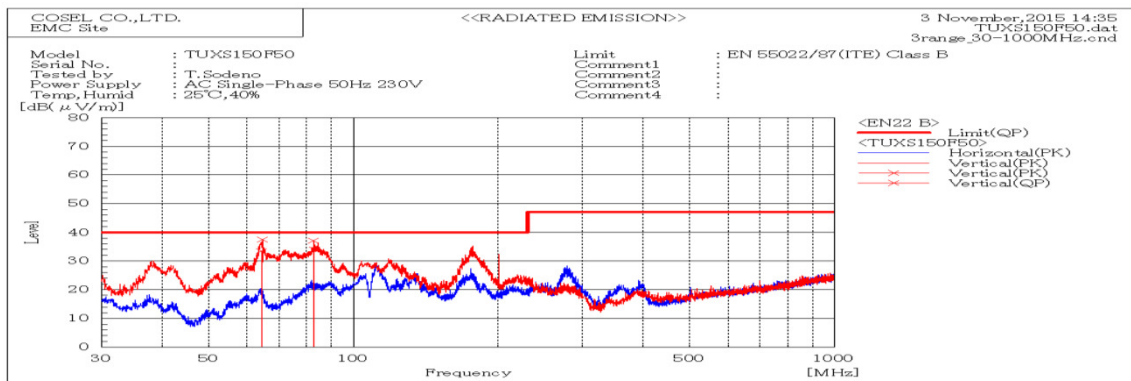


DATA SHEET		Date	04-Nov-15
Model	TUXS150F50	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno



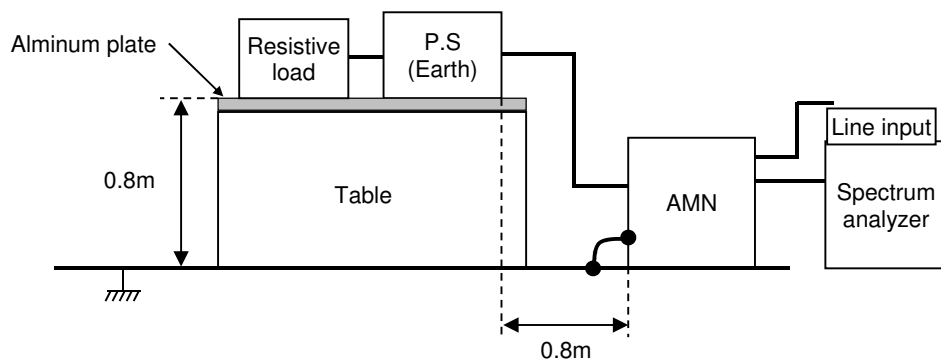
Frequency MHz	Line Phase	Reading dB(uV)	Factor dB	Level dB(uV)	Limit dB(uV)		Margin dB	Pass/ Fail
		QP		QP	QP	AV		
0.15706	VA	29.3	20.2	49.5	65.6	55.6	16.1	Pass
0.16182	VB	29.8	20.2	50	65.4	55.4	15.4	Pass
0.19217	VB	28.8	20.1	48.9	63.9	53.9	15	Pass
0.19233	VA	27.5	20.1	47.6	63.9	53.9	16.3	Pass
0.47715	VA	20.9	20	40.9	56.4	46.4	15.5	Pass



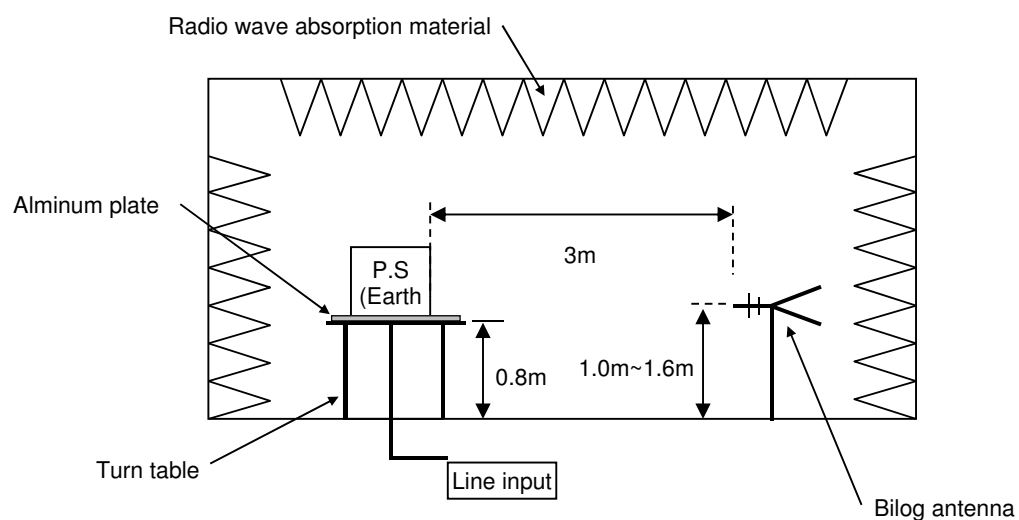
Frequency MHz	Polariz ation	Stabilit y	Reading dB(uV)	Factor dB(1/m)	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg
			QP		QP					
64.412	V	Stable	56.1	-22.6	33.5	40	6.5	Pass	112	154
82.851	V	Stable	54.7	-20.7	34	40	6	Pass	109	273

DATA SHEET		Date	04-Nov-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno

1. Line conduction



2. Radiated emission



Test: EMI

Model Name:TUXS150F50

○ Photographs of Test Set-Up

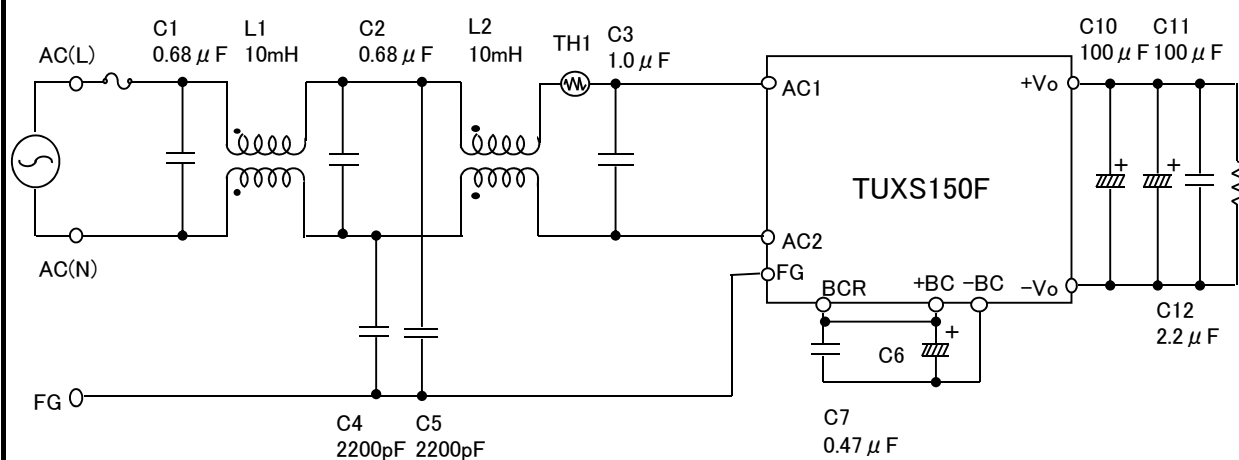
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1,L2 : SCR-040-0R8A100JH(NEC TOKIN)
 TH1 : 12D2-15LCS(SEMITEC)
 C1,C2 : LE684-MX(OKAYA)
 C3 : LE105-MX(OKAYA)
 C4,C5 : DE1E3KX222M(MURATA)
 C6 : EKXJ421ELL151MM50S(Nippon Chemi-con)
 C7 : AFS450V474K(OKAYA)
 C10,C11 : PCR1J101MCL1GS(NICHICON)
 C12 : GRM31CR72A225K(MURATA)